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United States Patent [19]

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Spurr et al.

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[54] **MASS SPECTROMETER SAMPLE SLIDE**

2178534 2/1987 United Kingdom 250/288

[75] Inventors: **John Spurr**, Hayward, Calif.; **John Cottrell**, London, United Kingdom

Primary Examiner—A. Hugo Word
Assistant Examiner—I. Simmons
Attorney, Agent, or Firm—Watson, Cole, Grindle & Watson

[73] Assignee: **Finnigan Mat Ltd.**, Herts, United Kingdom

[**] Term: **14 Years**

[57] **CLAIM**

The ornamental design for a mass spectrometer sample slide, as shown and described.

[21] Appl. No.: **680,682**

[22] Filed: **Apr. 3, 1991**

DESCRIPTION

[52] U.S. Cl. **D24/225**

FIG. 1 shows a perspective view of a mass spectrometer sample slide;

[58] Field of Search 250/288; D24/119, 133, D24/147, 225, 232

FIG. 2 shows a front elevation of a mass spectrometer sample slide;

[56] **References Cited**

U.S. PATENT DOCUMENTS

- D. 273,898 5/1984 Valencia D24/225
- D. 277,699 2/1985 Valencia D24/225
- 4,120,584 10/1978 Hodges et al. 250/288 X
- 4,745,277 5/1988 Banar et al. 250/288
- 4,879,458 11/1989 Brunfeldt et al. 250/288

FIG. 3 shows a side elevation of the mass spectrometer sample slide, the opposite side elevational view being identical thereto;

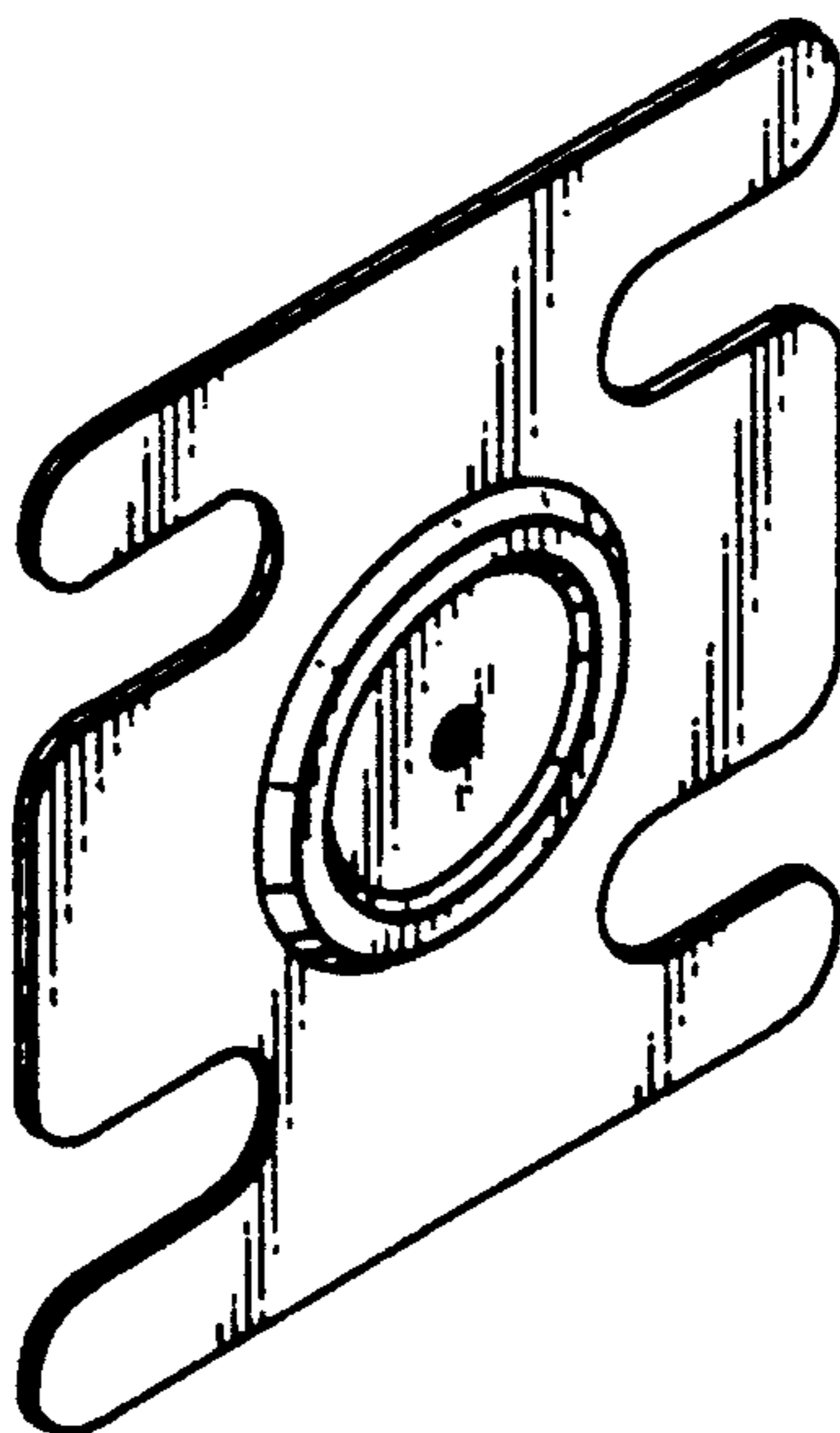
FOREIGN PATENT DOCUMENTS

- 8504281 9/1985 PCT Int'l Appl. 250/288
- 8504283 9/1985 PCT Int'l Appl. 250/288

FIG. 4 shows a top plan view of the mass spectrometer sample slide, the bottom plan view being identical thereto;

FIG. 5 shows a rear elevation of a mass spectrometer sample slide; and,

FIG. 6 shows a cross-sectional view of the mass spectrometer sample slide taken along the line 6—6 of FIG. 2.



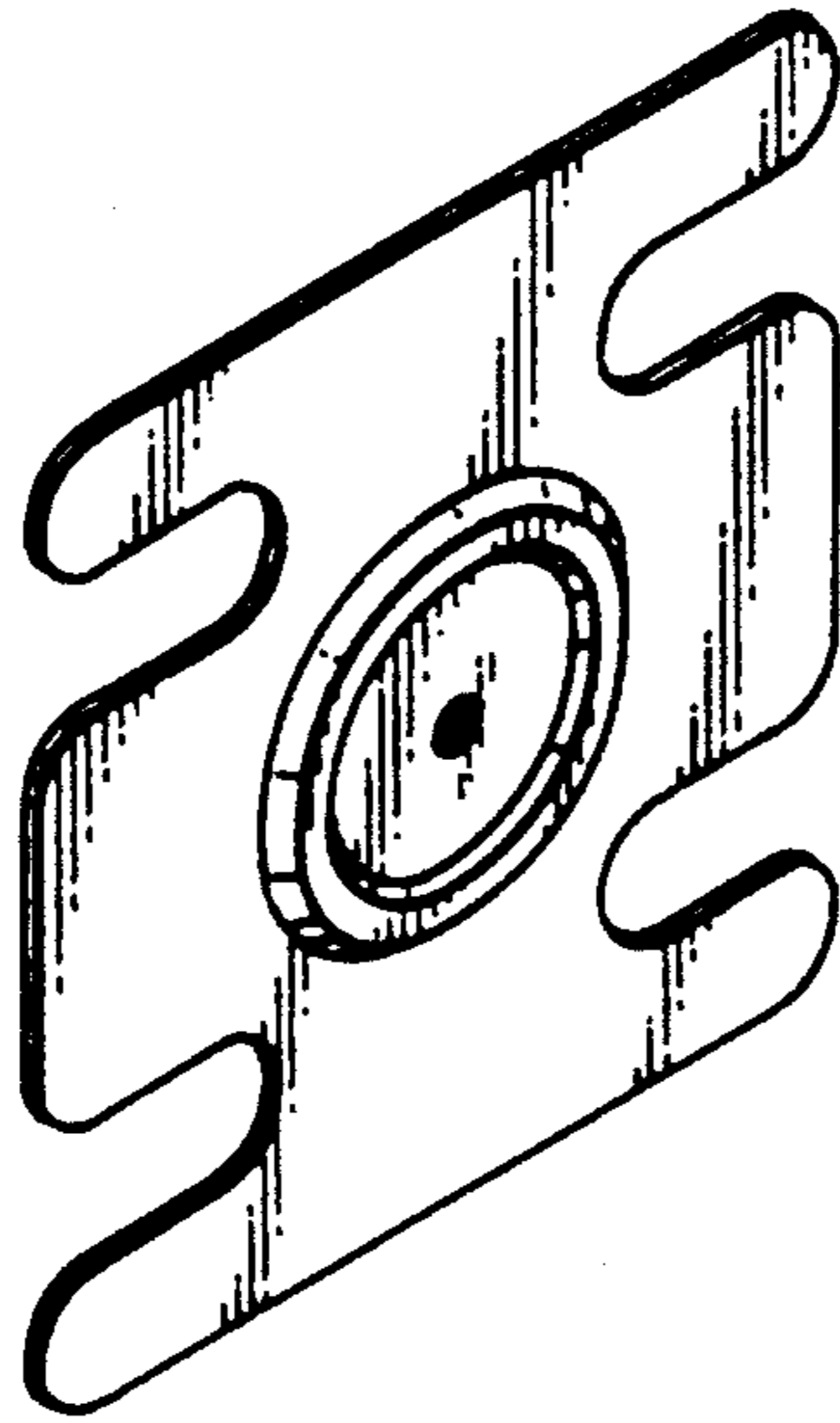


FIG. 1.

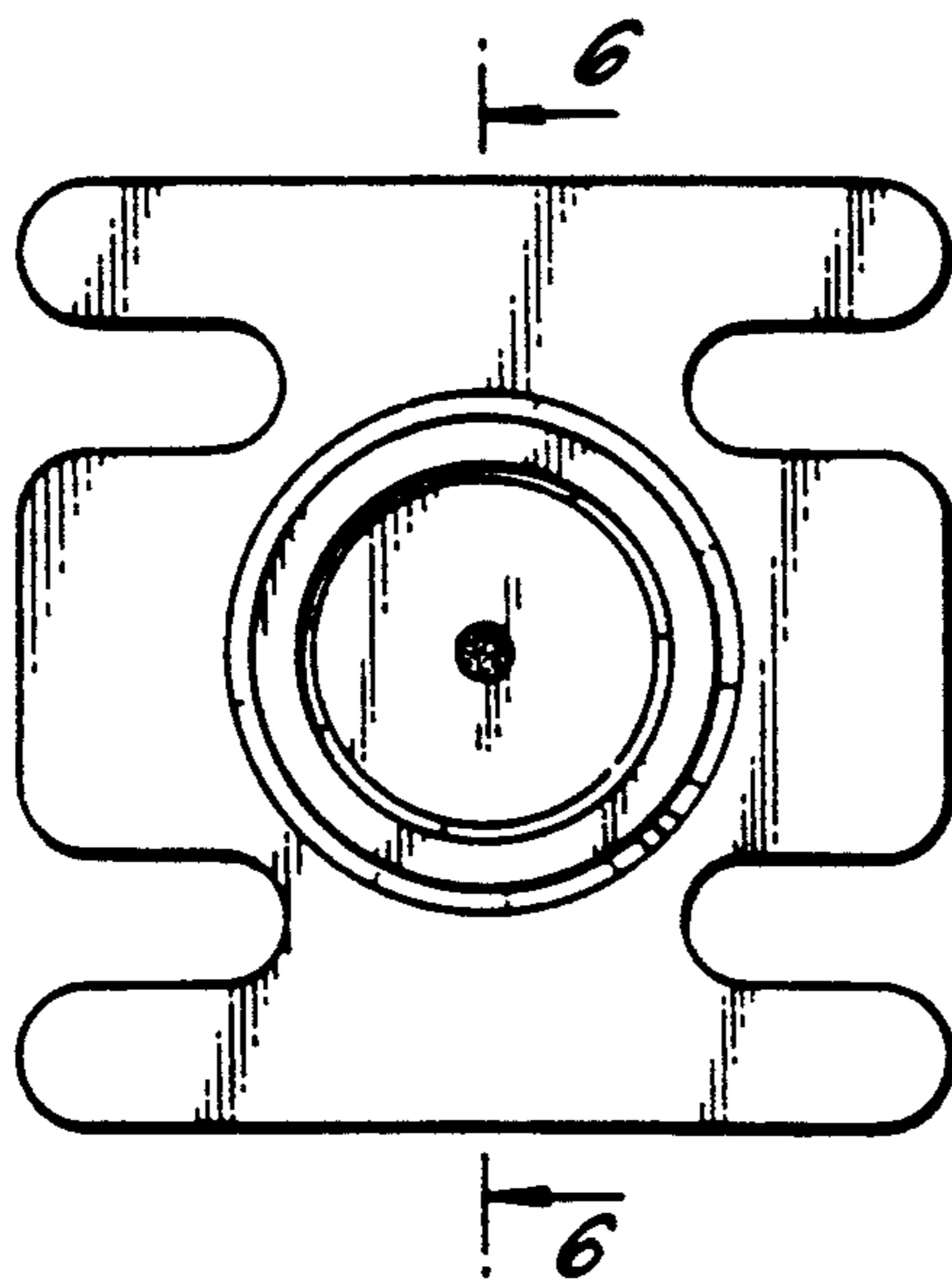


FIG. 2.



FIG. 3.



FIG. 4.

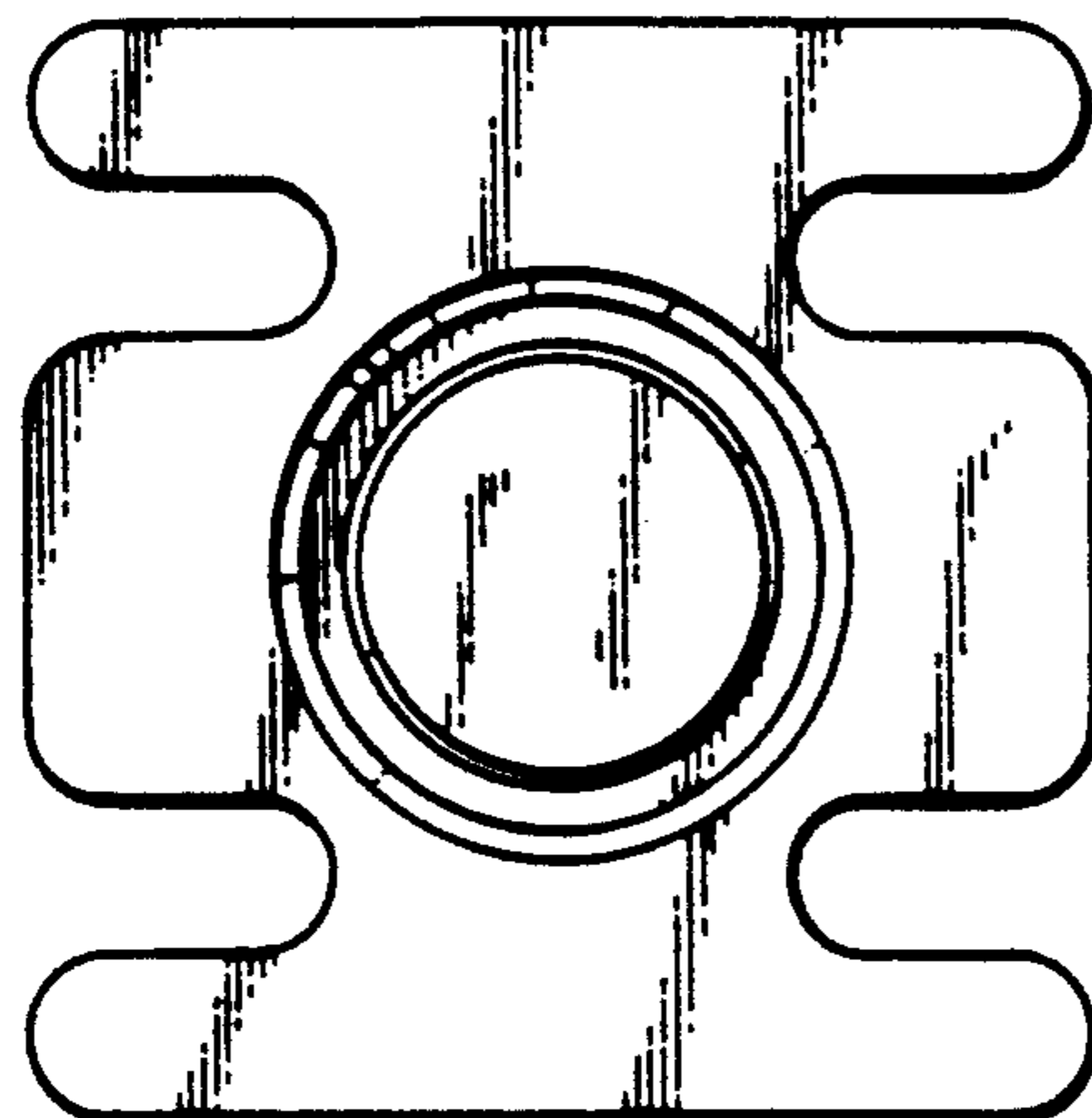


FIG. 5.



FIG. 6.